



Power MOSFETS

DATASHEET

LM30074NAI8A

N-Channel
Enhancement Mode MOSFET

- Leadpower-semiconductor Corp., Ltd
- sales@leadpower-semi.com
- (03) 6577339 FAX : (03) 6577229
- www.leadpower-semi.com

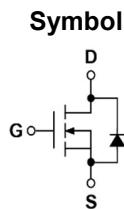
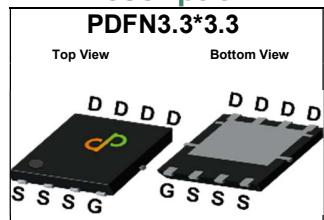


Quality Management Systems
ISO 9001:2015 Certificate

LM30074NAI8A

N-Channel Enhancement Mode MOSFET

Pin Description



Product Summary

Symbol	N-Channel	Unit
V_{DSS}	30	V
$R_{DS(ON)-Max}$	7.4	$m\Omega$
I_D	50	A

Feature

- Lower $R_{DS(ON)}$ to Minimize Conduction Losses
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and R_g Tested

Applications

- Portable Equipment
- Battery Powered System

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30074NAI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	30074 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Note : = Lot Code

Absolute Maximum Ratings ($T_J=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter		N-Channel	Unit
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		± 20	
T_J	Maximum Junction Temperature		150	$^\circ C$
T_{STG}	Storage Temperature Range		-55 to 150	$^\circ C$
$I_{DM}^{(1)}$	Pulse Drain Current Tested	$T_c=25^\circ C$	71	A
I_D	Continuous Drain Current	$T_c=25^\circ C$	50	A
		$T_c=100^\circ C$	32	
P_D	Maximum Power Dissipation	$T_c=25^\circ C$	30	W
		$T_c=100^\circ C$	12	
$I_{AS}^{(2)}$	Avalanche Current, Single pulse	$L=0.1mH$	21	A
$E_{AS}^{(2)}$	Avalanche Energy, Single pulse	$L=0.1mH$	22	mJ

Thermal Characteristics

Symbol	Parameter		Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	4.2	$^\circ C/W$
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	Steady State	95	$^\circ C/W$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature $150^\circ C$

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

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N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=250\mu\text{A}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=250\mu\text{A}$	1.1	1.6	2.1	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}, I_{\text{DS}}=8\text{A}$	-	6.2	7.4	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{DS}}=6\text{A}$	-	8.2	10.7	
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_{\text{DS}}=8\text{A}$	-	12	-	S
Dynamic Characteristics [®]						
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\text{V},$ $\text{Freq.}=1\text{MHz}$	-	3.5	-	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V},$ $V_{\text{DS}}=15\text{V},$ $\text{Freq.}=1\text{MHz}$	-	1094	-	pF
C_{oss}	Output Capacitance		-	147	-	
C_{rss}	Reverse Transfer Capacitance		-	127	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V},$ $I_{\text{D}}=1\text{A}, R_{\text{GEN}}=6\Omega$	-	6	-	nS
t_{r}	Turn-on Rise Time		-	22.5	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	48.6	-	
t_{f}	Turn-off Fall Time		-	19.8	-	
Q_{g}	Total Gate Charge	$V_{\text{GS}}=4.5\text{V}, V_{\text{DS}}=25\text{V}$ $I_{\text{D}}=8\text{A}$	-	16	-	nC
Q_{g}	Total Gate Charge	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=25\text{V},$ $I_{\text{D}}=8\text{A}$	-	31	-	
Q_{gs}	Gate-Source Charge		-	1.4	-	
Q_{gd}	Gate-Drain Charge		-	9.3	-	
Source-Drain Characteristics						
$V_{\text{SD}}^{\circledast}$	Diode Forward Voltage	$I_{\text{SD}}=1\text{A}, V_{\text{GS}}=0\text{V}$	-	0.7	1.1	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=1\text{A}, V_{\text{R}}=0\text{V}$	-	14	-	nS
Q_{rr}	Reverse Recovery Charge	$dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	-	5.6	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

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N-Channel Typical Characteristics

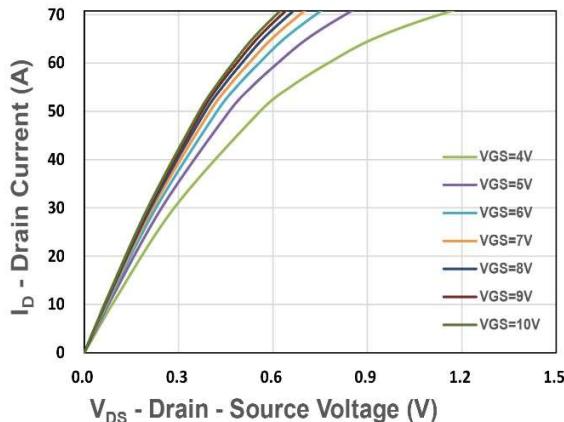


Figure 1. Output Characteristics

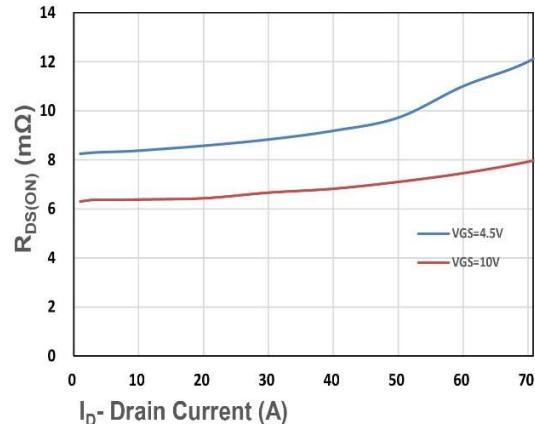


Figure 2. On-Resistance vs. ID

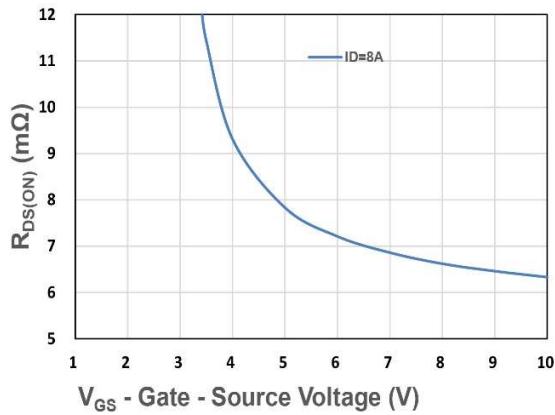


Figure 3. On-Resistance vs. VGS

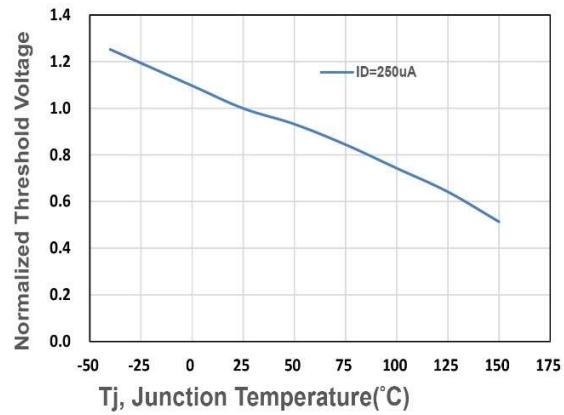


Figure 4. Gate Threshold Voltage

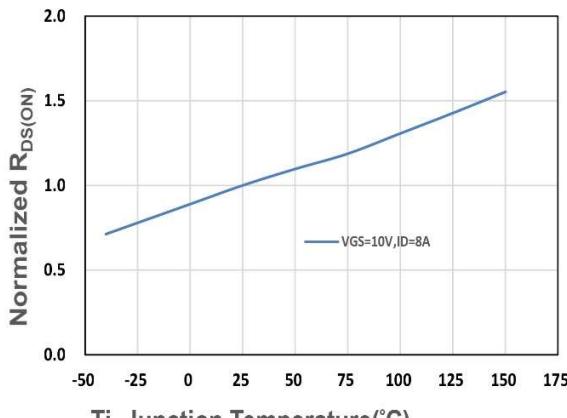


Figure 5. Drain-Source On Resistance

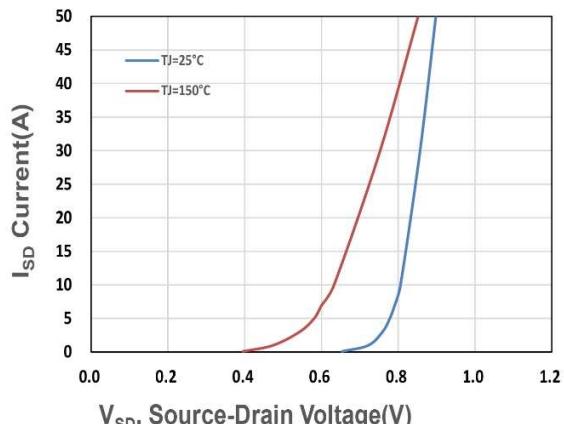


Figure 6. Source-Drain Diode Forward

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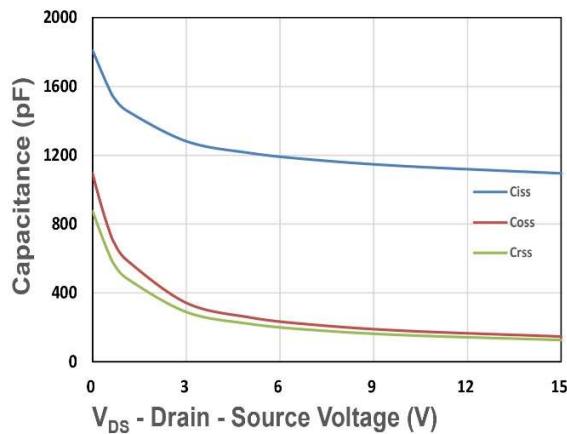


Figure 7. Capacitance

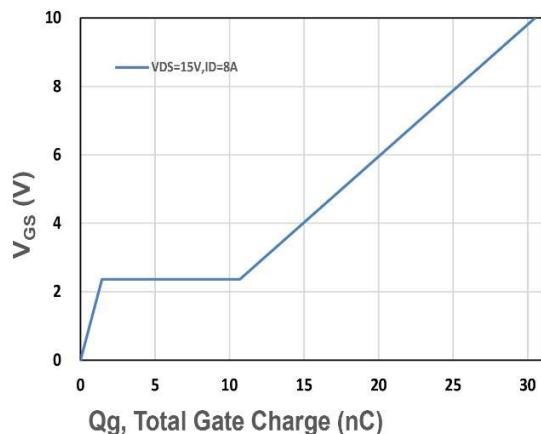


Figure 8. Gate Charge Characteristics

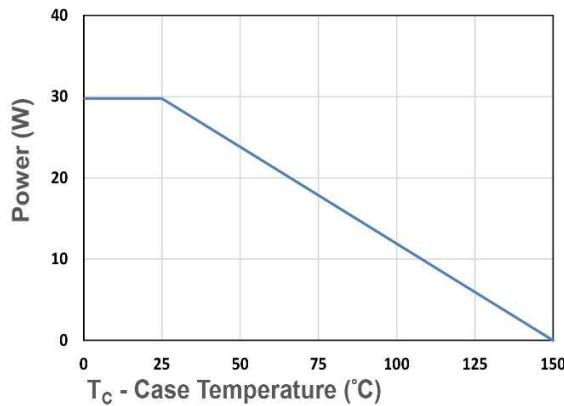


Figure 9. Power Dissipation

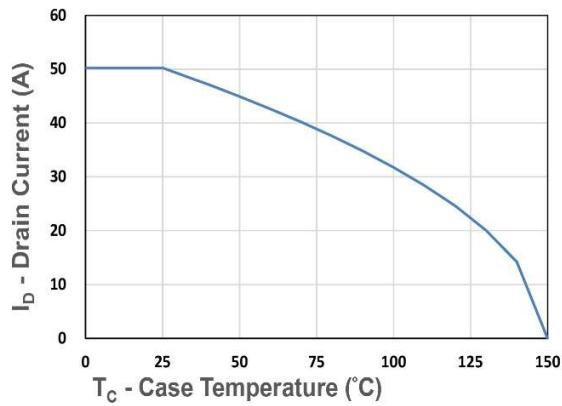


Figure 10. Drain Current

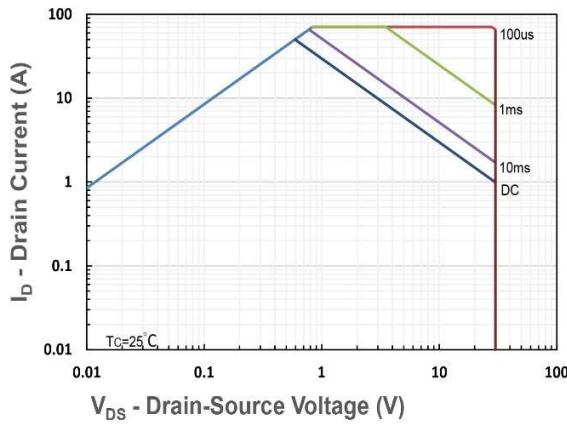


Figure 11. Safe Operating Area

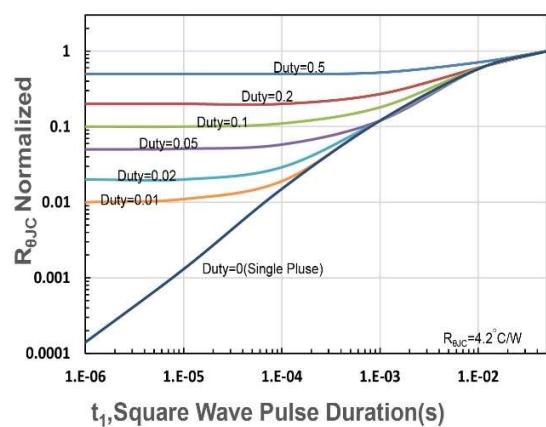


Figure 12. $R_{θJC}$ Transient Thermal Impedance